

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)				Docket No. ZIMR/0008		Serial No. Unassigned	
LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT				Applicant Schlichting		Confirmation No.: Unassigned	
(Use several sheets if necessary)				Filing Date		Group	
		Examiner	Unassigned		Herewith		Unassigned
U.S. Patent Documents							
*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
EN	A1	6,066,849	05/23/00	Masnaghetti, et al.	250	310	09/08/98
EN	A2	5,139,624	08/18/92	Searson, et al.	204	129.3	12/06/90
	A3						
	A4						
	A5						
	A6						
	A7						
	A8						
	A9						
	A10						
	A11						
	A12						
	A13						
Foreign Patent Documents							
*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation
							YES NO
EN	B1	1 047 104 A1	10/25/00	EP	H04F	37/305	<input type="checkbox"/> <input type="checkbox"/>
EN	B2	0 969 494 A1	01/05/00	EP	H10J	37/02	<input type="checkbox"/> <input type="checkbox"/>
	B3						<input type="checkbox"/> <input type="checkbox"/>
	B4						<input type="checkbox"/> <input type="checkbox"/>
	B5						<input type="checkbox"/> <input type="checkbox"/>
OTHER ART							
*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.					
EN	C1	Frosien, et al., "High Precision Electron Optical System for Absolute and CD-measurements on Large Substrates," Nuclear Instruments and Methods in Physics Research A 363 (1995) 25-30					
EN	C2	European Search Report, dated July 4, 2003 for EP 03000677.9					
	C3						
Examiner <i>EN</i>					Date Considered <i>09-06-04</i>		
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.							